

ANALYZER

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Abstract

PURPOSE:To prevent the mechanical and magnetic deviation of the beam line axis of a radiating beam in a device to analyze a sample by radiating the beam to the sample.

CONSTITUTION:In a device to analyze a sample by radiating a beam to the sample, a through hole 2 to pass a radiating beam and a beam measuring part 3 to measure the radiating beam are arranged in different positions on a circumferential surface of a rotary body 1 in axial symmetry. The rotary body 1 is rotatably supported with a shaft crossing at a right angle to a beam line on the beam line between a beam source 40 and the sample as a rotary shaft, and the penetration of the radiating beam and the introduction to the beam measuring part 3 are switched to/from each other by rotation of the rotary body 1.

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